

<b>Notice of References Cited</b>	Application/Control No. 10/783,856	Applicant(s)/Patent Under Reexamination BADT ET AL.	
	Examiner Uyen T. Le	Art Unit 2163	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0182394	09-2003	Ryngler et al.	709/217
*	B	US-2004/0122896	06-2004	Gourraud, Christophe	709/204
*	C	US-6,771,991	08-2004	Gupta et al.	455/566
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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**NON-PATENT DOCUMENTS**

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